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ECE142: Electronic Circuits Summer 2014

# Sheet 1 Semiconductor Review

T=300	Si	Ge	GaAs
$n_i (cm^{-3})$	$1.45 \times 10^{10}$	$2.4 \times 10^{13}$	$1.8 \times 10^{6}$
$\mu_n$ (cm <sup>2</sup> /Vs)	1500	3900	8500
$\mu_{\rm p}$ (cm <sup>2</sup> /Vs)	450	1900	400

## Problem 1

- **a)** Explain qualitatively the differences in intrinsic carrier concentrations  $(n_i)$  for Ge, Si and GaAs. (Why is  $n_i$  highest for Ge? Why is it lowest for GaAs?)
- **b**) Explain qualitatively why  $n_i$  increases with increasing temperature.

### Problem 2

Consider a Si sample under equilibrium conditions, doped with Boron to a concentration  $10^{17}$  cm<sup>-3</sup>.

- **a**) At T = 300K, is this material n-type or p-type?
- **b**) What are the majority and minority carrier concentrations?

### Problem 3

Consider a Si sample maintained at T = 300K under equilibrium conditions, doped with Boron to a concentration  $2 \times 10^{16}$  cm<sup>-3</sup>:

- a) What are the electron and hole concentrations (*n* and *p*) in this sample? Is it n-type or p-type?
- **b**) Suppose the sample is doped additionally with Phosphorus to a concentration  $6 \times 10^{16}$  cm<sup>-3</sup>. Is the material now n-type or p-type? What is the resistivity of this sample?

#### Problem 4

Ultra-thin semiconductor materials are of interest for future nanometer-scale transistors, but can present undesirably high resistance to current flow. How low must the resistivity of a semiconductor material be, to ensure that the resistance of a 2nm-thick, 10nm-long, 100nm-wide region does not exceed 100 ohms? If this material is n-type Si, estimate the dopant concentration that would be needed to achieve this resistivity.

#### Problem 5

A silicon sample maintained at 300 K under thermal equilibrium has a non-uniform doping concentration profile, such that the electron concentration, n, varies linearly from  $1 \times 10^{12}$  cm<sup>-3</sup> to  $5 \times 10^{17}$  cm<sup>-3</sup> while going from point  $x_1$  to point  $x_2$ . Assume that the mobility is constant at 1000 cm<sup>2</sup>/Vs throughout the sample.



- **a**) Calculate the diffusion coefficient,  $D_n$  (in cm<sup>2</sup>/s) for the electrons
- **b)** Plot the diffusion current density  $(A/cm^2)$  for the electrons as a function of x. Mark the numerical value on the graph. (Hint: What is the equation for diffusion current density?)

#### **Problem 6**

Explain using words and figures the four basic semiconductor fabrication processes.